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IN RE APPLICATION OF:

Masayuki OIKAWA, et al.

GROUP: 2872

SERIAL NO: 10/574,286

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EXAMINER:

FOR:

INSPECTION METHOD AND INSPECTION ASSISTING DEVICE FOR QUARTZ PRODUCT OF SEMICONDUCTOR PROCESSING APPARATUS

SUBMISSION OF SUPPLEMENTAL APPLICATION DATA SHEET

Office of Initial Patent Examination Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Applicant(s) submit herewith a Supplemental Application Data Sheet for the aboveidentified application for the purpose of removing the Assignment Data.

Respectfully Submitted,

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